

### **General Description**

The BSC070N10NS5 use advanced SGT MOSFET

technology to provide low RDS(ON), low gate charge,

fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness and suitable.

### **General Features**

V<sub>DS</sub> =100V I<sub>D</sub> =75A

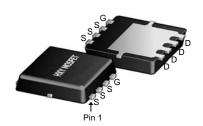
 $R_{DS(ON)}$  < 9.2m $\Omega$ @  $V_{GS}$ =10V

## **Applications**

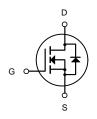
Consumer electronic power supply Motor control

Synchronous-rectification Isolated DC

Synchronous-rectification applications



DFN5X6-8L



N-Channel MOSFET

# **Package Marking and Ordering Information**

| Product ID   | Pack      | Brand      | Qty(PCS) |
|--------------|-----------|------------|----------|
| BSC070N10NS5 | DFN5X6-8L | HXY MOSFET | 5000     |

## **Absolute Maximum Ratings** at T<sub>j</sub>=25°C unless otherwise noted

| Parameter                                    | Symbol         | Value      | Unit |
|----------------------------------------------|----------------|------------|------|
| Drain source voltage                         | VDS            | 100        | V    |
| Gate source voltage                          | VGS            | ±20        | V    |
| Continuous drain current <sup>1)</sup>       | ID             | 75         | А    |
| Pulsed drain current <sup>2)</sup>           | ID, pulse      | 300        | Α    |
| Power dissipation <sup>3)</sup>              | P <sub>D</sub> | 97         | W    |
| Single pulsed avalanche energy <sup>5)</sup> | EAS            | 90         | mJ   |
| Operation and storage temperature            | Tstg, Tj       | -55 to 150 | °C   |
| Thermal resistance, junction-case            | RθJC           | 1.3        | °C/W |



### N-SGT Enhancement Mode MOSFET

# **Electrical Characteristics** (T<sub>J</sub>=25°C unless otherwise specified)

| Symbol               | Parameter                                                | Test Condition                                            | Min. | Тур. | Max. | Units |
|----------------------|----------------------------------------------------------|-----------------------------------------------------------|------|------|------|-------|
| V <sub>(BR)DSS</sub> | Drain-Source Breakdown Voltage                           | V <sub>GS</sub> =0V, I <sub>D</sub> =250μA                | 100  | -    | -    | V     |
| I <sub>DSS</sub>     | Zero Gate Voltage Drain Current                          | V <sub>DS</sub> =100V, V <sub>GS</sub> =0V,               | -    | -    | 1.0  | μA    |
| I <sub>GSS</sub>     | Gate to Body Leakage Current                             | V <sub>DS</sub> =0V, V <sub>GS</sub> = ±20V               | -    | -    | ±100 | nA    |
| V <sub>GS(th)</sub>  | Gate Threshold Voltage                                   | V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250µA  | 1.0  | 1.6  | 2.5  | V     |
| D                    | Static Drain-Source on-Resistance                        | V <sub>GS</sub> =10V, I <sub>D</sub> =20A                 | -    | 7.3  | 9.2  | mΩ    |
| R <sub>DS(on)</sub>  | note3                                                    | V <sub>GS</sub> =4.5V, I <sub>D</sub> =8A                 | -    | 9    | 13.5 | mΩ    |
| C <sub>iss</sub>     | Input Capacitance                                        | \/ -50\/ \/ -0\/                                          | -    | 2046 | -    | рF    |
| Coss                 | Output Capacitance                                       | V <sub>DS</sub> =50V, V <sub>GS</sub> =0V,<br>f=1.0MHz    | -    | 865  | -    | pF    |
| Crss                 | Reverse Transfer Capacitance                             | I=I.UIVIDZ                                                | -    | 25   | -    | pF    |
| Qg                   | Total Gate Charge                                        | V 50V I 20A                                               | -    | 39.4 | -    | nC    |
| Q <sub>gs</sub>      | Gate-Source Charge                                       | V <sub>DS</sub> =50V, I <sub>D</sub> =30A,                | -    | 5.2  | -    | nC    |
| Q <sub>gd</sub>      | Gate-Drain("Miller") Charge                              | V <sub>GS</sub> =10V                                      | -    | 9.8  | -    | nC    |
| t <sub>d(on)</sub>   | Turn-on Delay Time                                       |                                                           | -    | 20   | -    | ns    |
| t <sub>r</sub>       | Turn-on Rise Time                                        | V <sub>DD</sub> =50V, I <sub>D</sub> =25A,                | -    | 5.2  | -    | ns    |
| t <sub>d(off)</sub>  | Turn-off Delay Time                                      | $R_G=6\Omega$ , $V_{GS}=10V$                              | -    | 49   | -    | ns    |
| t <sub>f</sub>       | Turn-off Fall Time                                       |                                                           | -    | 12   | -    | ns    |
| Is                   | Maximum Continuous Drain to Source Diode Forward Current |                                                           | -    | -    | 75   | А     |
| I <sub>SM</sub>      | Maximum Pulsed Drain to Source Diode Forward Current     |                                                           |      | -    | 300  | Α     |
| V <sub>SD</sub>      | Drain to Source Diode Forward Voltage                    | V <sub>GS</sub> =0V, I <sub>S</sub> =30A                  | -    | -    | 1    | V     |
| t <sub>rr</sub>      | Body Diode Reverse Recovery Time                         |                                                           | -    | 49   | -    | ns    |
| Qrr                  | Body Diode Reverse Recovery<br>Charge                    | T <sub>J</sub> =25℃,<br>I <sub>F</sub> =12A,dI/dt=100A/μs | -    | 85   | -    | nC    |

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

- 2. EAS condition: TJ=25  $^{\circ}$ C, VDD=50V, VG=10V, RG=25 $\Omega$ , L=0.5mH, IAS=19A
- 3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%



# **Typical Performance Characteristics**

Figure1: Output Characteristics

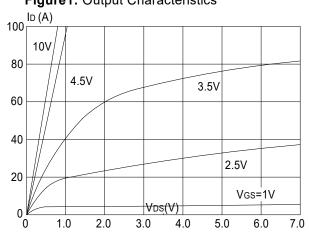


Figure 2: Typical Transfer Characteristics

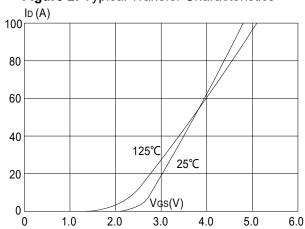


Figure 3:On-resistance vs. Drain Current

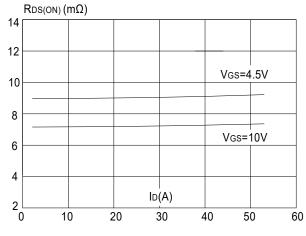


Figure 4: Body Diode Characteristics

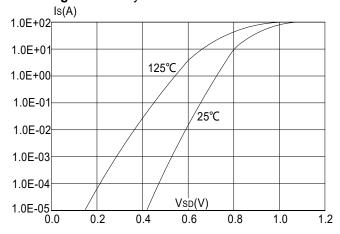


Figure 5: Gate Charge Characteristics

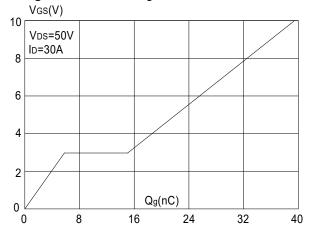
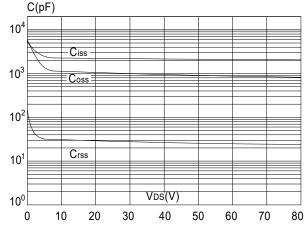
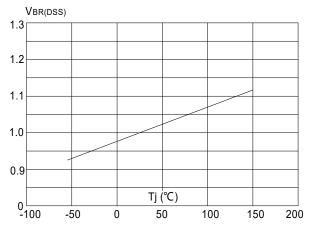


Figure 6: Capacitance Characteristics





**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



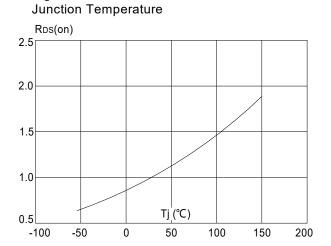
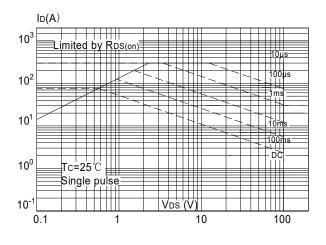


Figure 8: Normalized on Resistance vs.

Figure 9: Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature

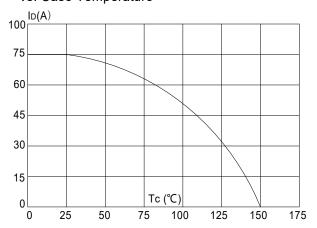
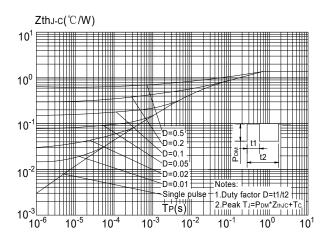


Figure.11: Maximum Effective
Transient Thermal Impedance, Junction-to-Case



## **Test Circuit**

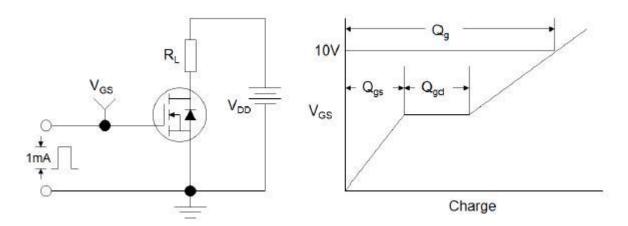


Figure1:Gate Charge Test Circuit & Waveform

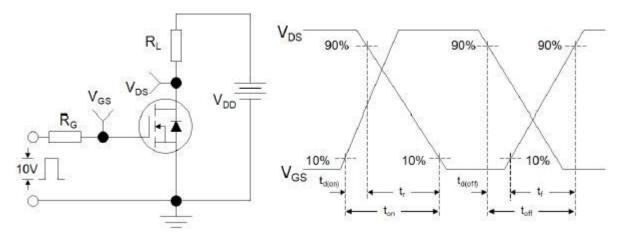


Figure 2: Resistive Switching Test Circuit & Waveforms

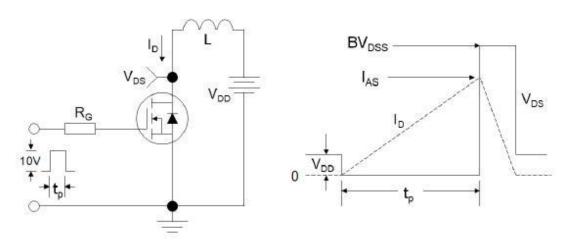
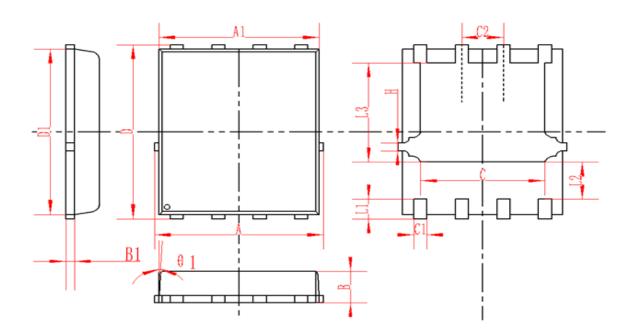


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

# **DFN5X6-8L Package Information**



| SYMBOL | MM       |         | INCH     |       |        |       |
|--------|----------|---------|----------|-------|--------|-------|
|        | MIN      | NOM     | MAX      | MIN   | NOM    | MAX   |
| А      | 4.95     | 5       | 5.05     | 0.195 | 0.197  | 0.199 |
| A1     | 4.82     | 4.9     | 4.98     | 0.190 | 0.193  | 0.196 |
| D      | 5.98     | 6       | 6.02     | 0.235 | 0.236  | 0.237 |
| D1     | 5.67     | 5.75    | 5.83     | 0.223 | 0.226  | 0.230 |
| В      | 0.9      | 0.95    | 1        | 0.035 | 0.037  | 0.039 |
| B1     | 0.254REF |         | 0.010REF |       |        |       |
| С      | 3.95     | 4       | 4.05     | 0.156 | 0.157  | 0.159 |
| C1     | 0.35     | 0.4     | 0.45     | 0.014 | 0.016  | 0.018 |
| C2     |          | 1.27TYP |          |       | 0.5TYP |       |
| θ1     | 8°       | 10°     | 12°      | 8°    | 10°    | 12°   |
| L1     | 0.63     | 0.64    | 0.65     | 0.025 | 0.025  | 0.026 |
| L2     | 1.2      | 1.3     | 1.4      | 0.047 | 0.051  | 0.055 |
| L3     | 3.415    | 3.42    | 3.425    | 0.134 | 0.135  | 0.135 |
| Η      | 0.24     | 0.25    | 0.26     | 0.009 | 0.010  | 0.010 |



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